

**Search Notes**

Application/Control No.

10/717,284

Examiner

Hiep Nguyen

Applicant(s)/Patent under  
Reexamination

TAFT ET AL.

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner
327	541	10.18.04	162
	539	↓	↓
	540		
	391	↓	↓

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See attachment	06.17.05	162